



Muon MDT Front End Electronics (WBS 1.5.9)

James Shank



DOE/NSF Review of U.S. ATLAS Detector

(with help from: E. Hazen, J. Oliver, C. Posch)

DOE/NSF Review of ATLAS, 1 Mar 2000, BNL



MDT Front End Electronics

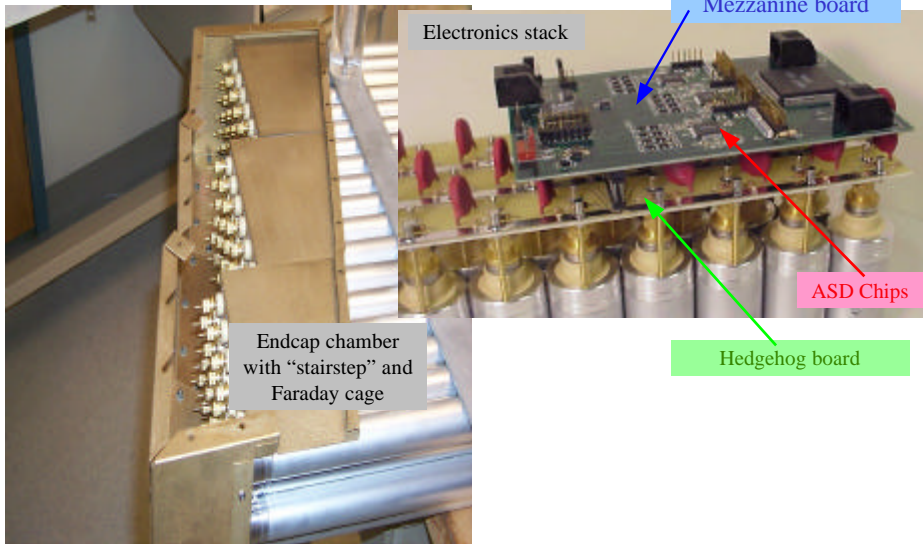
Overview:

- The major deliverables:
 - ◆ Amplifier/Shaper/Discriminator (ASD) Chip
 - ◆ “Hedgehog” Boards
 - ◆ “Mezzanine” Boards
- Cost drivers
- Schedule issues





The Major Components



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MDT Operation Principles

Proportional drift tube

- Position measured from drift time

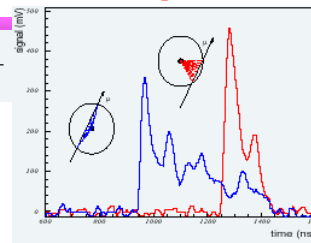


Operating Point

- Ar/Co₂ 93%/7% gas mixture
- 3 bar gas pressure
- 2×10^4 gas gain

Performance:

- ~ 700 ns maximum drift time
- 80 mm resolution/tube

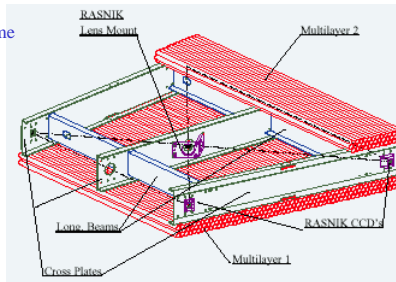


Mechanical Layout

- 30 mm Ø Al tube 400 µm thick wall
- 50 µm Ø W-Re anode.
- Two 3 or 4 tube layers/chamber
- 1194 chambers
- 370,000 readout channels

Mechanical tolerance

- Wire/tube: 10 mm
- Wire/chamber: 20 mm
- 100 mm concentricity tubes-wire.
- Monitored with RASNIK system

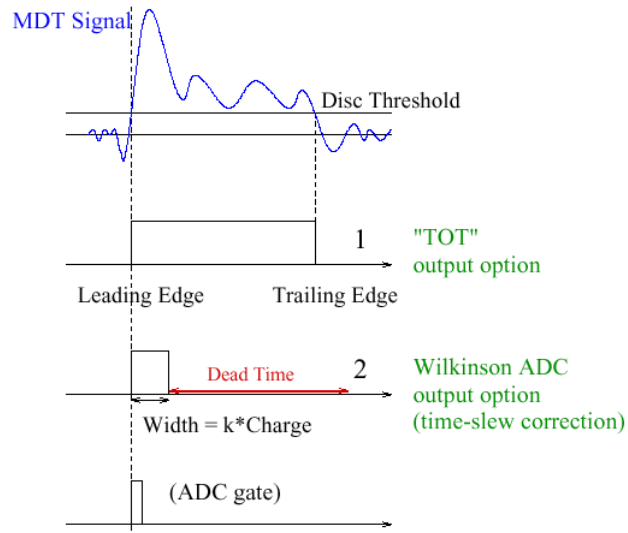


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ASD Functionality



Near-term deliverables

- **Electronics for chamber "Module 0"s**
 - ◆ **ASD lite**
 - 4 channel version with limited functionality
 - ◆ **Mezzanine lite**
 - CERN TDC (existing) + logic to control ASD lite
 - ◆ **Standard Hedgehog boards**
 - ◆ **10,000 channels being produced for 11 worldwide chamber construction sites.**



ASD Lite

- **ASD Lite Features**
 - ◆ 4 channel complete Amp./Shaper/Discr.
 - ◆ Externally controlled threshold, hysteresis, bias
 - ◆ Linear output for 1 channel
- **Status**
 - ◆ Extensively tested on-chamber
 - ◆ 16k chips produced. 4400 packaged
 - ◆ Semi-automatic testing completed (yield 95%)
- **Remaining:**
 - ◆ Assemble and test on Mezzanine boards.

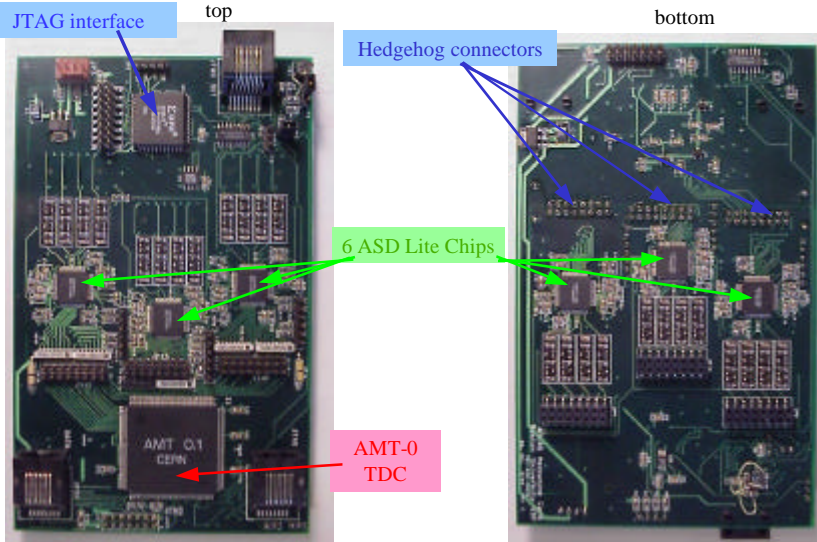


Mezzanine Lite

- **24 Channel board with TDC**
- **JTAG Programming of Thresholds**
- **Mezz. Board is plug-compatible with final TDC**
- **10 boards produced and tested**
- **Full system test with CSM-0 (custom VME board for TDC readout) starting mid-March**
- **Components ordered, minor board layout changes being finalized**



Mezzanine Lite



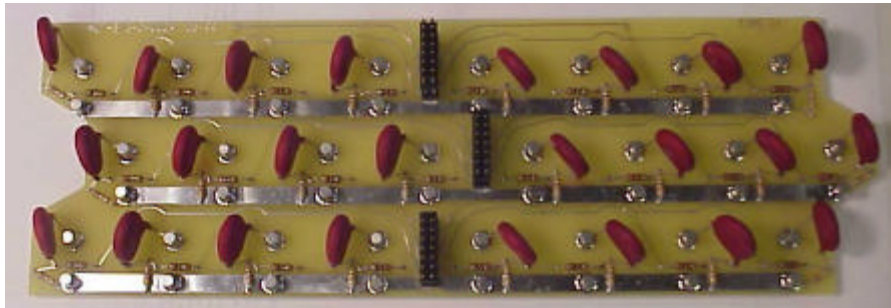
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Hedgehog Boards

- 24 Channel board mounts directly on tubes. Blocks HV, carries signal to Mezzanine board
- Prototypes tested by various collaborators
 - ◆ First production of 100 boards completed
- 300 needed for chamber Module 0's



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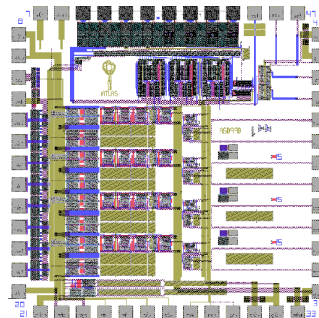
Production ASD Chip-History

- ◆ 1996: Integrated 1.2 μm CMOS Preamp+Disc prototyped
- ◆ 1997: Changed to HP 0.5 μm process ASD+LVDS
 - Confirmed specs in new process, evaluated LVDS outputs
- ◆ 1998: Develop ASD lite full 4-channel chip
 - Reduced crosstalk from 5% to 0.3% (unmeasurable)
 - Demonstrated stable operation on chamber, met all specs
 - Changed baseline design for new gas mixture (bipolar shaping)
- ◆ 1999: Package+test 4400 ASD lites, prototype ADC, logic
 - Demonstrated high yield (95%). Tight parameter control in production
 - Built and tested Wilkinson ADC on chamber
 - Developed and submitted programmable ASD lite
- ◆ 2000: Beam test validation of analog path, first Octal ASD
 - Submit, test bipolar shaping
 - Test programmable ASD lite
 - Full, programmable Octal prototype development underway (Posch)
- ◆ 2001: Second Octal prototype (production prototype)
- ◆ 2002: Finish ASD Production



Production ASD Chip

- On going ASD development work:
 - ◆ Wilkinson ADC
 - ◆ Bipolar shaping
 - ◆ Programmable Control and Charge injection
 - ◆ 8 channels/chip





ASD Programmable features

1) Test pulse injection

3-bit capacitor select	10 R ² - 80 R ² (8 switched 50 pF - capacitors @ 200mV)	3
8-bit mask register	select channels for calibration injection	8

2) Discriminators

Location	Variable	DAC type	Res	LSB	Range	comments	
DISC1	Threshold: V _{DD} /2 ± 128mV complementary, > 4 times nominal threshold (± 30mV)	VDAC (R-chain)	8-bit	1 mV	256 mV	at last gain stage (DA4 input)	8
	Hysteresis: 0 - 20mV (0 - 7 prin. Electrons), @ threshold coupling	CDAC	4-bit	1.875 uA	300 uA	0 - 100mV hysteresis at DISC1	4
DISC2	Threshold: 0 - 128 mV	VDAC (R-chain)	4-bit	16 mV	128 mV		4
	Hysteresis: fixed						

3) Wilkinson ADC

Variable	Nominal, adjustable range	DAC type	Res	LSB	range	
run down -current	I _{source} = 70 ns, 35 ns - 140 ns	CDAC	4-bit	1 uA	16 uA	4
gate (time window) width	T _{gate} = 15 ns, 8 ns - 64 ns	-	5-bit	-	-	5
dead time	T _{dead} = 10 - 20 ns, 0 - 1024 ns	-	4-bit	-	-	4

4) DC Offset (most probably eliminated in bipolar version)

Variable	adjustable range	DAC type	Res	LSB	range	
DC level after 1. shaper/gain stage	few 100 mV	2 x CDAC	4-bit	-	16 uA	8

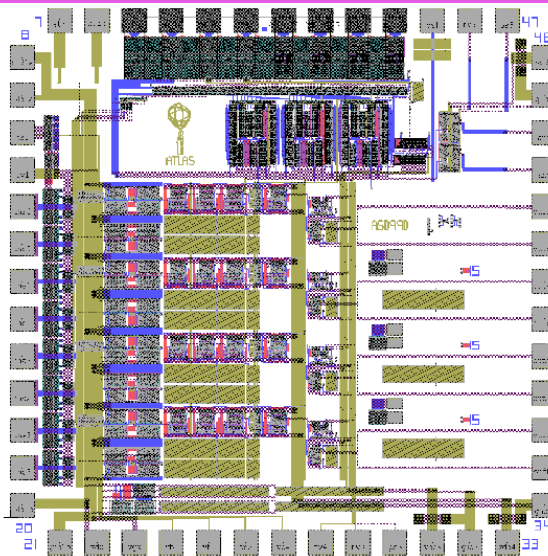
5) Output

Channel mode	HI, LO, Active, Disable (GND) preamp	2-bit / channel	16
Chip mode	TOT (Time Over Threshold), ADC	1-bit	1

Total bits: 57 (63)



4 Channel ASD Layout

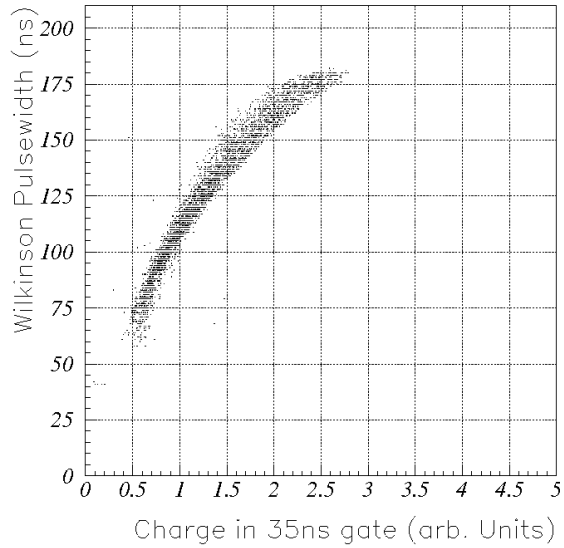




ASD Lite Recent Measurements

Tests of the Wilkinson ADC
(conventional capacitor run-down technique)

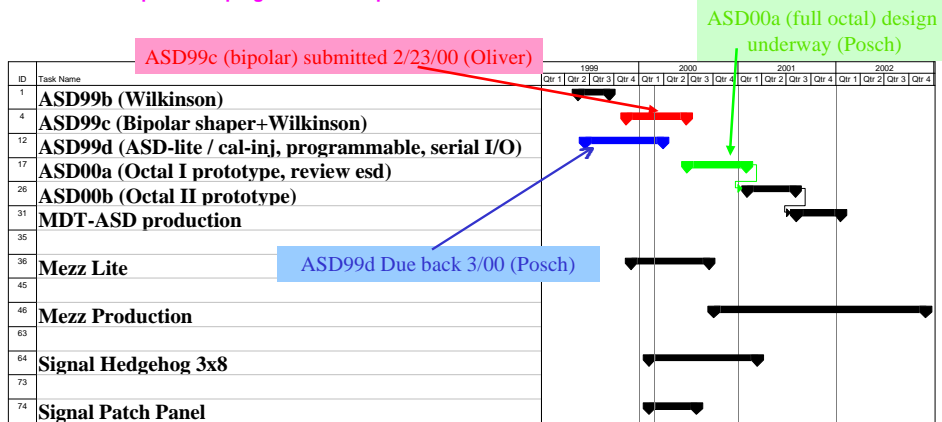
Tests performed on a prototype chamber with Am source.



Production ASD Status

- **Production Schedule**

- ◆ Wilkinson ADC for Time Walk Correction Tested Summer 99
- ◆ Complete programmability/charge injection Test chip due 3/00
- ◆ Bipolar Shaping Test chip submitted 2/23/00





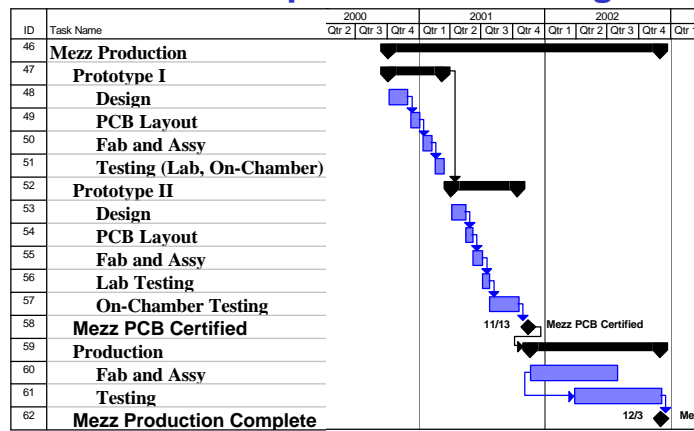
Cost Drivers

- **Total ETC 1.5.9 ~ \$3.7 M**
 - ◆ **Mezzanine cards (Qty. 15,479)**
 - \$117. Each \$1.9M
 - 4 layer board
 - ◆ **ASD (Qty. 65,824)**
 - \$780k
 - Most engineering already complete
 - ◆ **Hedgehog boards (Qty. 4400)**
 - \$103. Each \$460k
 - Expensive HV coating



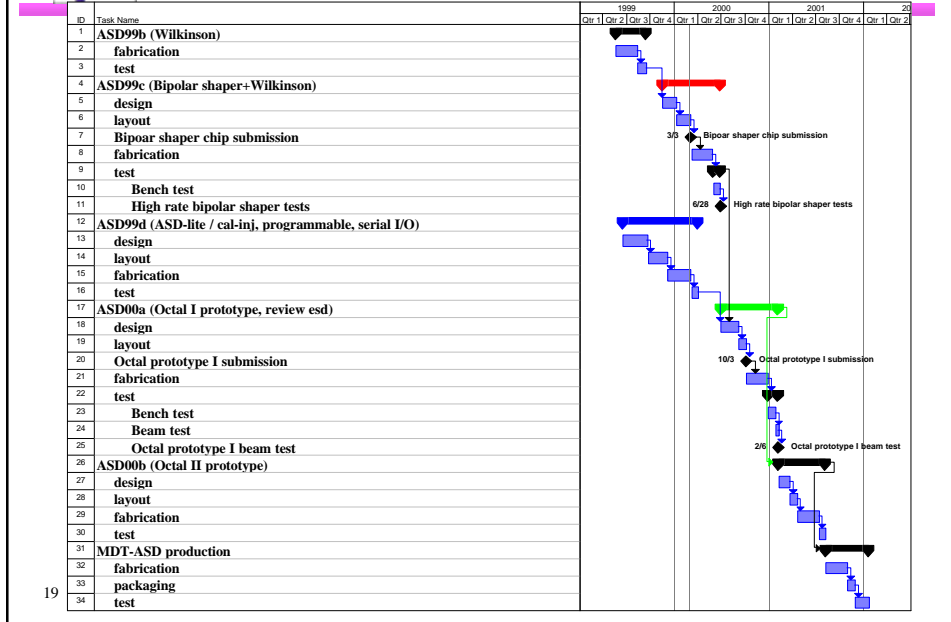
Critical Path Items

- **ASD development/production**
- **Mezzanine board production/testing**





Critical Path Items: ASD



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Summary

- Most design issues solved.
- Schedule slipped ~9 months from baseline
 - ◆ Not too bad a match with world-wide chamber construction.
- Very close to original 1997 budget